Se	arc	ch	No	te	S
II EE11				1161	112

I PREIDING	 11218 (181 (184)

Application/Control No.	Applicant(s Reexamina
10/766 322	MIVAET

Examiner

Jay M. Patidar

Applicant(s)/Pat Reexamination	ent under
MIYA ET AL.	
Art Unit	

2862

SEARCHED				
Class	Subclass	Date	Examiner	
324	207.18	6/12/2006	JP	
		·		
		,		

INTERFERENCE SEARCHED			
Subclass	Date	Examiner	
207.18	6/12/2006	JP	
207.25			
. 			
٠			
	Subclass 207.18	Subclass Date 207.18 6/12/2006	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
search updated.	6/12/2006	JP
·- ·		
	_	